12/19/03

Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.			SERIAL NO.	
(Modified)		PATENT AND TRAC	EMARK OFFICE	246770US2CIP			NEW APPLICATION	
APPLICANT								
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Toshiki TAKAHASHI, et al.				
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U.S. PATENT DOCUMENTS								
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY			TRANSLATION YES NO	
100	AO	EP 0 786 794 A2	07-30-1997	EUROPE			X	
MA	AP	10-12597	01-16-1998	JAPAN				х
M	AQ	6-29259	02-04-1994	JAPAN		:		X
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
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Examiner	1.	ln 6/	1			Date Considered 3/15/06		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								
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